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## IN THE CLAIMS

- 1. (Currently amended) An integrated circuit (IC) comprising a signal transmission channel (TX) including radio frequencies and an integrated tester (TEST) intended to test radio characteristics of said integrated circuit, said tester (TEST) comprising: first means (COUPL) for recovering a part of the signal generated by the transmission channel (TX) at a first frequency (F0), second means (M) for converting said recovered signal from the first frequency (F0) into a second frequency (F1), an amplifier (A) for amplifying said signal at this second frequency (F1), and a rectifier (R) for rectifying said signal.
- 2. (Currently amended) An integrated circuit (IC) as claimed in claim 1, eharacterized in that wherein the tester further comprises detection means (CMP/ADC) for detecting the validity of the signal generated by the transmission channel (TX).
- 3. (Currently amended) An integrated circuit (IC) as claimed in claim 1, characterized in that wherein the tester further comprises a filter (F) for filtering harmonics of the signal.
- 4. (Currently amended) An integrated circuit (IC) as claimed in claim 1, characterized in that wherein the first frequency (F0) is a radio frequency and the second frequency (F1) is a low frequency.
- 5. (Currently amended) A method of testing an integrated circuit (IC)-comprising a signal transmission channel (TX)-including radio frequencies, said method being intended to

test radio characteristics of said integrated circuit and being independent of said transmission channel, said method comprising the following steps: recovering a part of the signal generated by the transmission channel (TX) at a first frequency (F0), converting the first frequency (F0) of the recovered signal into a second frequency (F1), amplifying said signal at this second frequency (F1), and rectifying said signal.

- 6. (Currently amended) A method of testing an integrated circuit (IC) as claimed in claim
- 5, eharacterized in that it further comprisinges a step of detecting the validity of the signal generated by the transmission channel-(TX).
- 7. (Currently amended) A method of testing an integrated circuit (IC) as claimed in claim
- 5, characterized in that it comprisinges a step of filtering harmonics of said signal.
- 8. (Currently amended) A tester (TEST) for testing radio characteristics of a transmission channel (TX) of an integrated circuit (IC), said tester (TEST) being intended to be integrated with said integrated circuit (IC) and comprising: first means (COUPL) for recovering a part of the signal generated by the transmission channel (TX) at a first frequency (F0) second means (M) for converting said signal recovered from the first frequency (F0) into a second frequency (F1) an amplifier (A) for amplifying said signal to this second frequency (F1), and a rectifier (R) for rectifying said signal.
- 9. (Currently amended) A tester as claimed by claim 8, characterized in that it further comprisinges detection means (CMP/ADC) for detecting the validity of the signal

generated by the transmission channel-(TX).

- 10. (Currently amended) A tester as claimed by claim 8, characterized in that it further comprisinges a filter (F) for filtering harmonics of said signal.
- 11. (Currently amended) A transmitter comprising an integrated circuit (IC) comprising a tester as claimed in claim 8.